

N-Channel 650V (D-S) Super Junction Power MOSFET

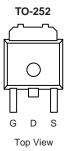
PRODUCT SUMMARY					
V_{DS} (V) at T_J max.	650				
R _{DS(on)} max. at 25 °C (Ω)	V _{GS} = 10 V	0.50			
Q _g max. (nC)	25				
Q _{gs} (nC)	2.0				
Q _{gd} (nC)	2.7				
Configuration	Single				

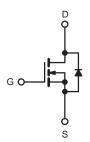
FEATURES

- \bullet Low figure-of-merit (FOM) $R_{on} \ x \ Q_g$
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Qg)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial





N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	650		
Gate-Source Voltage			V _{GS}	± 30	V	
Continuous Drain Current (T,I = 150 °C)	V _{GS} at 10 V	T _C = 25 °C	- I _D	9	А	
Continuous Drain Current (1) = 150 °C)	V _{GS} at 10 V	T _C = 100 °C		6		
Pulsed Drain Current ^a			I _{DM}	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy b			E _{AS}	86	mJ	
Maximum Power Dissipation			P _D	83	W	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Drain-Source Voltage Slope	$T_J = 1$	25 °C	d) / / d+	50	\//	
Reverse Diode dV/dt ^d			dV/dt	4.5	V/ns	
Soldering Recommendations (Peak Temperature) c for 10 s			300	°C		

- a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD}=50$ V, starting $T_J=25$ °C, L=28.2 mH, $R_g=25$ Ω , $I_{AS}=3.5$ A.
- c. 1.6 mm from case.
- d. $I_{SD} \le I_D$, $dI/dt = 100 \text{ A/}\mu\text{s}$, starting $T_J = 25 \,^{\circ}\text{C}$.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	63	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.6	G/ VV		

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static				•	,		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		2	-	4	V
			V _{GS} = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	I_{GSS}		$V_{GS} = \pm 30 \text{ V}$		-	± 1	μA
			$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$		-	1	
Zero Gate Voltage Drain Current	I _{DSS}		', V _{GS} = 0 V, T _J = 125 °C	-	-	10	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 4 A	-	0.50	-	Ω
Forward Transconductance	9 _{fs}		= 30 V, I _D = 4 A	-	16	-	S
Dynamic		_		1	ı	ı	
Input Capacitance	C _{iss}		V = 0 V	-	360	_	
Output Capacitance	C _{oss}	1	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$ f = 1 MHz		25	-	pF
Reverse Transfer Capacitance	C _{rss}	7			12	-	
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V _{DS} = 0 V to 520 V, V _{GS} = 0 V		-	45	-	
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	62	-	
Total Gate Charge	Qg			-	25		†
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_{D} = 4 \text{ A}, V_{DS} = 520 \text{ V}$		-	2.0	-	nC
Gate-Drain Charge	Q _{gd}	1		-	2.7	-	1
Turn-On Delay Time	t _{d(on)}			-	25	-	ns
Rise Time	t _r	Von	$V_{DD} = 520 \text{ V}, I_D = 4 \text{ A}, V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		55	-	
Turn-Off Delay Time	t _{d(off)}	00			70	-	
Fall Time	t _f				40	-	
Gate Input Resistance	R _g	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	A
Pulsed Diode Forward Current	I _{SM}			-	-	18	
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 4 A, V _{GS} = 0 V		-	-	1.5	V
Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = I _S = 4 A, dl/dt = 100 A/µs, V _R = 400 V		-	190	-	ns
Reverse Recovery Charge	Q _{rr}			-	2.3	-	μC
Reverse Recovery Current	I _{RRM}			<u> </u>	10	_	A

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

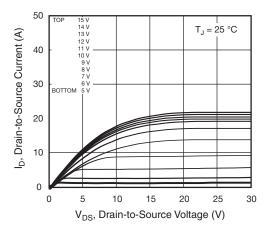


Fig. 1 - Typical Output Characteristics

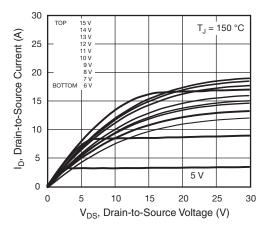


Fig. 2 - Typical Output Characteristics

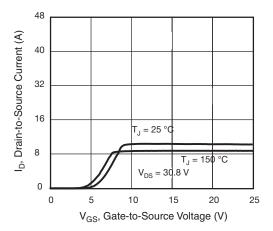


Fig. 3 - Typical Transfer Characteristics

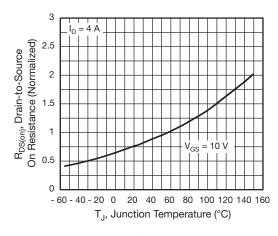


Fig. 4 - Normalized On-Resistance vs. Temperature

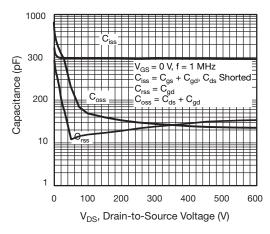


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

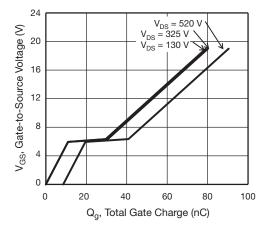


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



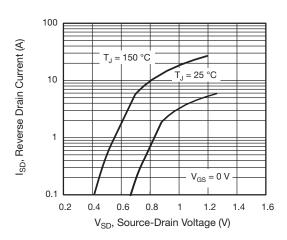


Fig. 7 - Typical Source-Drain Diode Forward Voltage

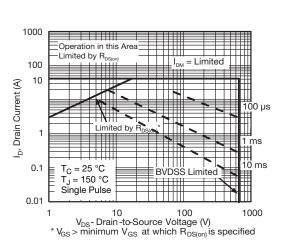


Fig. 8 - Maximum Safe Operating Area

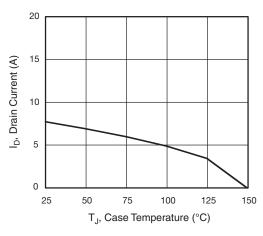


Fig. 9 - Maximum Drain Current vs. Case Temperature

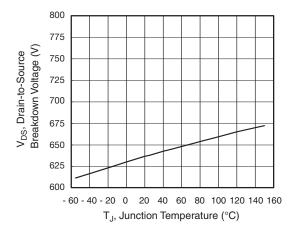


Fig. 10 - Temperature vs. Drain-to-Source Voltage

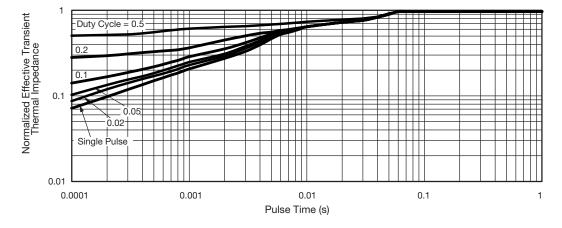


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case

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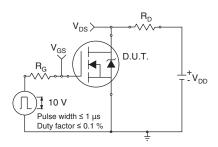


Fig. 12 - Switching Time Test Circuit

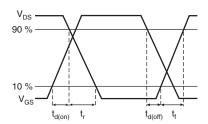


Fig. 13 - Switching Time Waveforms

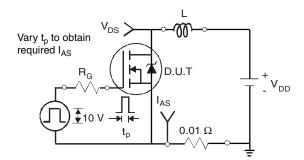


Fig. 14 - Unclamped Inductive Test Circuit

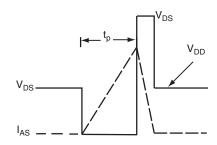


Fig. 15 - Unclamped Inductive Waveforms

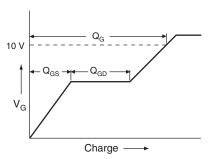


Fig. 16 - Basic Gate Charge Waveform

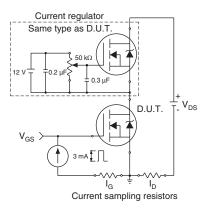
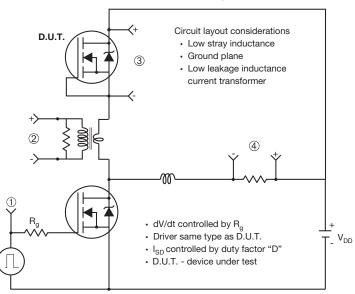


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



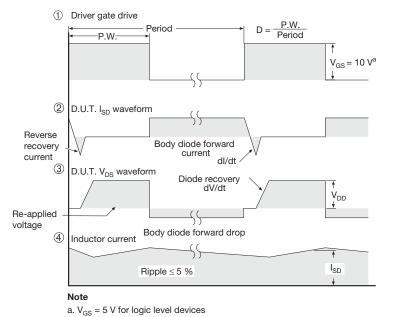
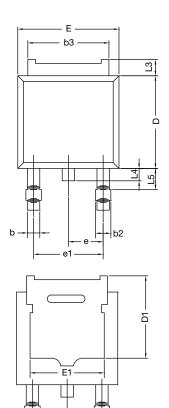
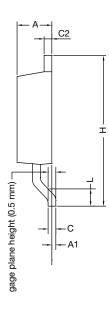


Fig. 18 - For N-Channel



TO-252AA CASE OUTLINE





	MILLIN	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	5.21	-	0.205	-	
Е	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28	BSC	0.090 BSC		
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.14	1.52	0.045	0.060	
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347					

Note

• Dimension L3 is for reference only.



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